

# GSM3414S

## 20V N-Channel Enhancement Mode MOSFET

### Product Description

GSM3414S, N-Channel enhancement mode MOSFET, uses Advanced Trench Technology to provide excellent  $R_{DS(ON)}$ , low gate charge.

These devices are particularly suited for low voltage power management, such as smart phone and notebook computer and other battery powered circuits, and low in-line power loss are needed in commercial industrial surface mount applications.

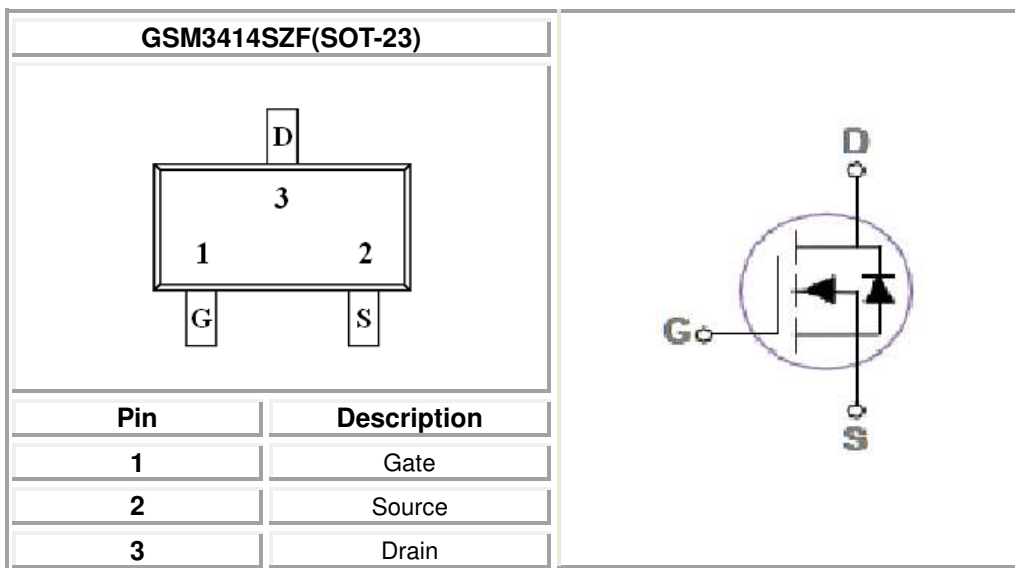
### Features

- 20V/5.8A,  $R_{DS(ON)}=25m\Omega@V_{GS}=4.5V$
- Super high density cell design for extremely low  $R_{DS(ON)}$
- Exceptional on-resistance and maximum DC current capability
- SOT-23 package design

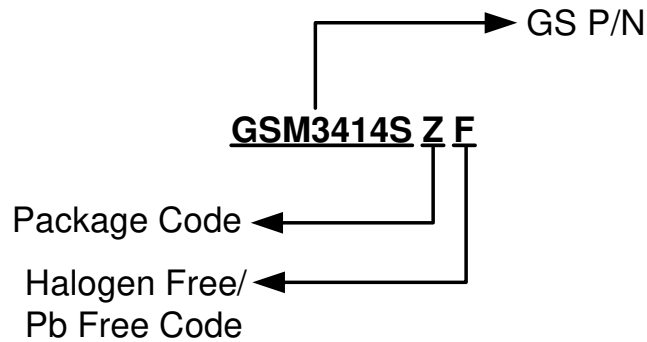
### Applications

- Portable Equipment
- Battery Powered System
- Net Working System

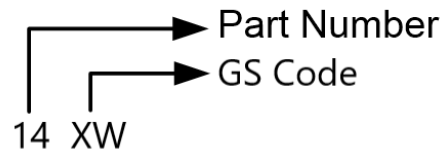
### Packages & Pin Assignments



## Ordering Information



## Marking Information



Part Number	Package	Part Marking	Quantity
GSM3414SZF	SOT-23	14XW	3000pcs

## Absolute Maximum Ratings

T<sub>A</sub>=25°C unless otherwise noted

Symbol	Parameter	Typical	Unit
V <sub>DS</sub>	Drain-Source Voltage	20	V
V <sub>GS</sub>	Gate –Source Voltage	±10	V
I <sub>D</sub>	Continuous Drain Current(T <sub>J</sub> =150°C)	T <sub>A</sub> =25°C	5.8
		T <sub>A</sub> =100°C	3.7
I <sub>DM</sub>	Pulsed <sup>1</sup> Drain Current	23.2	A
P <sub>D</sub>	Power Dissipation	T <sub>A</sub> =25°C	1.56
		T <sub>A</sub> =25°C	0.012
T <sub>J</sub>	Operating Junction Temperature	-55/150	°C
T <sub>STG</sub>	Storage Temperature Range	-55/150	°C
R <sub>θJA</sub>	Thermal Resistance-Junction to Ambient	80	°C/W

## Electrical Characteristics

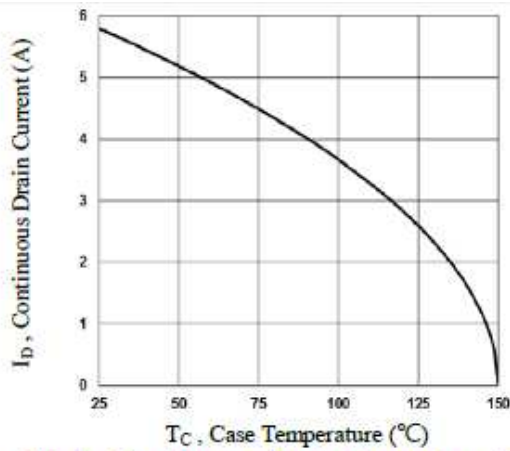
T<sub>A</sub>=25°C unless otherwise noted

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
<b>Static</b>						
V <sub>(BR)DSS</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> =0V, I <sub>D</sub> =250μA	20			V
V <sub>GS(th)</sub>	Gate Threshold Voltage	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =250μA	0.4	0.6	0.8	V
	V <sub>GS(th)</sub> Temperature Coefficient			2		mV/°C
ΔBVDSS /ΔT <sub>J</sub>	BVDSS Temperature Coefficient	Reference to 25°C, I <sub>D</sub> =1mA		0.02		V/°C
I <sub>GSS</sub>	Gate Leakage Current	V <sub>DS</sub> =0V, V <sub>GS</sub> =±10V			±100	nA
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> =16V, V <sub>GS</sub> =0V T <sub>J</sub> =25°C			1	μA
		V <sub>DS</sub> =16V, V <sub>GS</sub> =0V, T <sub>J</sub> =85°C			10	
R <sub>DS(on)</sub>	Drain-Source On-Resistance	V <sub>GS</sub> =4.5V, I <sub>D</sub> =4A		20	25	mΩ
		V <sub>GS</sub> =2.5V, I <sub>D</sub> =3A		27	35	
		V <sub>GS</sub> =1.8V, I <sub>D</sub> =2A		39	55	
g <sub>FS</sub>	Forward Transconductance	V <sub>DS</sub> =10V, I <sub>D</sub> =3A		6.5		S
<b>Dynamic</b>						
I <sub>S</sub>	Continuous Source Current	V <sub>D</sub> =V <sub>G</sub> =D <sub>V</sub> , Force Current			5.8	A
I <sub>SM</sub>	Pulsed Source Current				23.2	
V <sub>SD</sub>	Diode Forward Voltage	I <sub>S</sub> =1A, V <sub>GS</sub> =0V, T <sub>J</sub> =25°C			1	V
C <sub>iss</sub>	Input Capacitance	V <sub>DS</sub> =10V, V <sub>GS</sub> =0V, f=1MHz		535	775	pF
C <sub>oss</sub>	Output Capacitance			60	85	
C <sub>rss</sub>	Reverse Transfer Capacitance			34	50	
Q <sub>g</sub>	Total Gate Charge <sup>2</sup> 、 <sup>3</sup>	V <sub>DS</sub> =10V, V <sub>GS</sub> =4.5V, I <sub>D</sub> =4A		7.7	11	nC
Q <sub>gs</sub>	Gate-Source Charge <sup>2</sup> 、 <sup>3</sup>			0.9	1	
Q <sub>gd</sub>	Gate-Drain Charge <sup>2</sup> 、 <sup>3</sup>			2.4	5	
t <sub>d(on)</sub>	Turn-On Time <sup>2</sup> 、 <sup>3</sup>	V <sub>DD</sub> =10V, R <sub>G</sub> =25Ω, I <sub>D</sub> =1A, V <sub>GS</sub> =4.5V		4.1	8	ns
T <sub>r</sub>				11.6	22	
t <sub>d(off)</sub>	Turn-Off Time <sup>2</sup> 、 <sup>3</sup>			23.9	45	
T <sub>f</sub>				7.6	14	

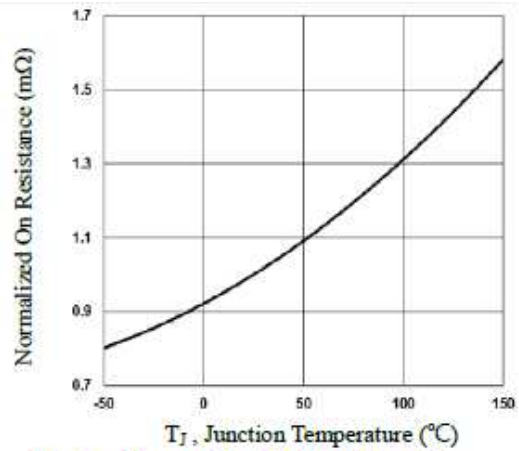
Note :

1. Repetitive Rating : Pulsed width limited by maximum junction temperature.
2. The data tested by pulsed , pulse width ≤ 300us , duty cycle ≤ 2%.
3. Essentially independent of operating temperature.

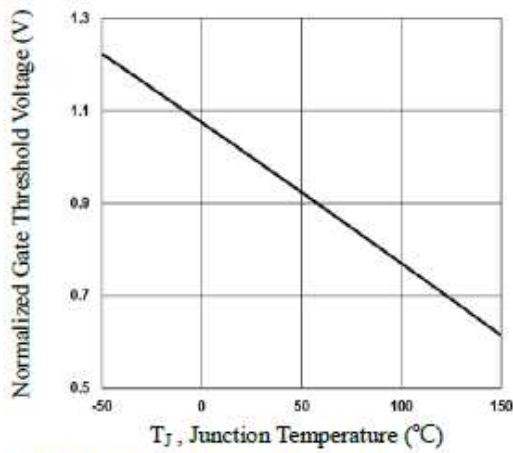
## Typical Performance Characteristics



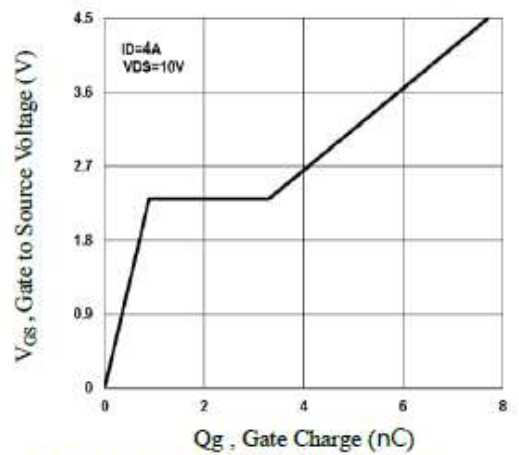
**Fig.1** Continuous Drain Current vs.  $T_C$



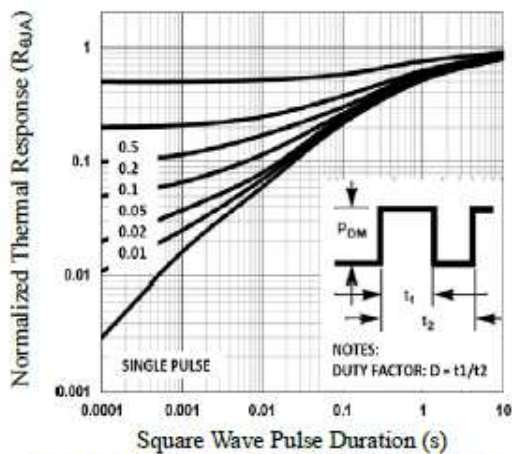
**Fig.2** Normalized  $R_{DS(on)}$  vs.  $T_J$



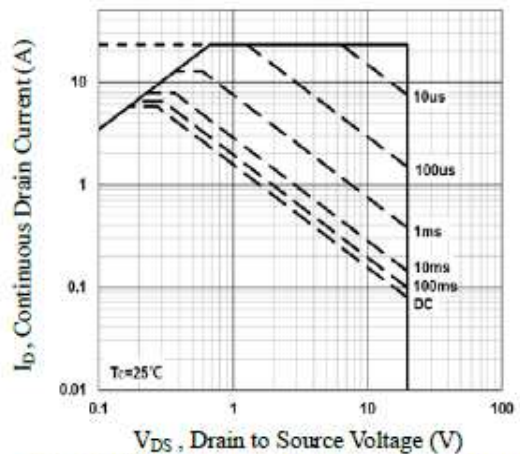
**Fig.3** Normalized  $V_{th}$  vs.  $T_J$



**Fig.4** Gate Charge Waveform



**Fig.5** Normalized Transient Impedance



**Fig.6** Maximum Safe Operation Area

Typical Performance Characteristics (continue)

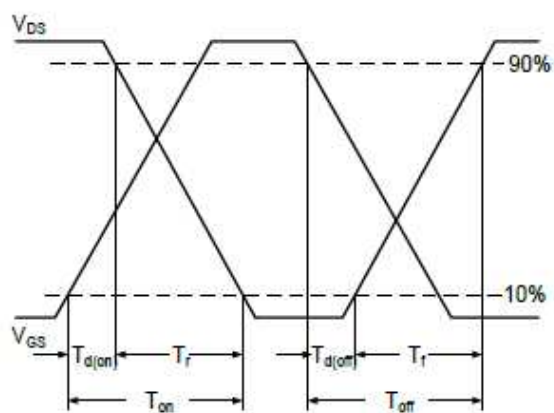


Fig.7 Switching Time Waveform

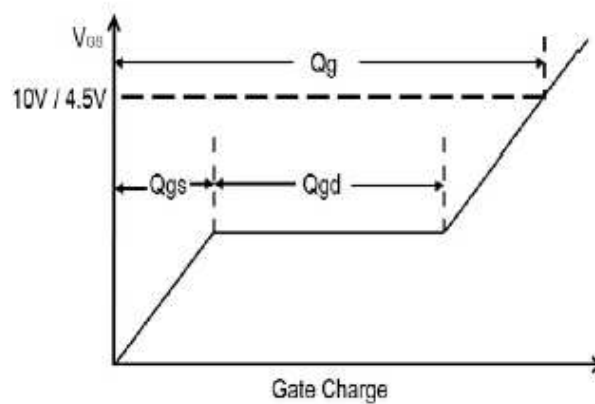
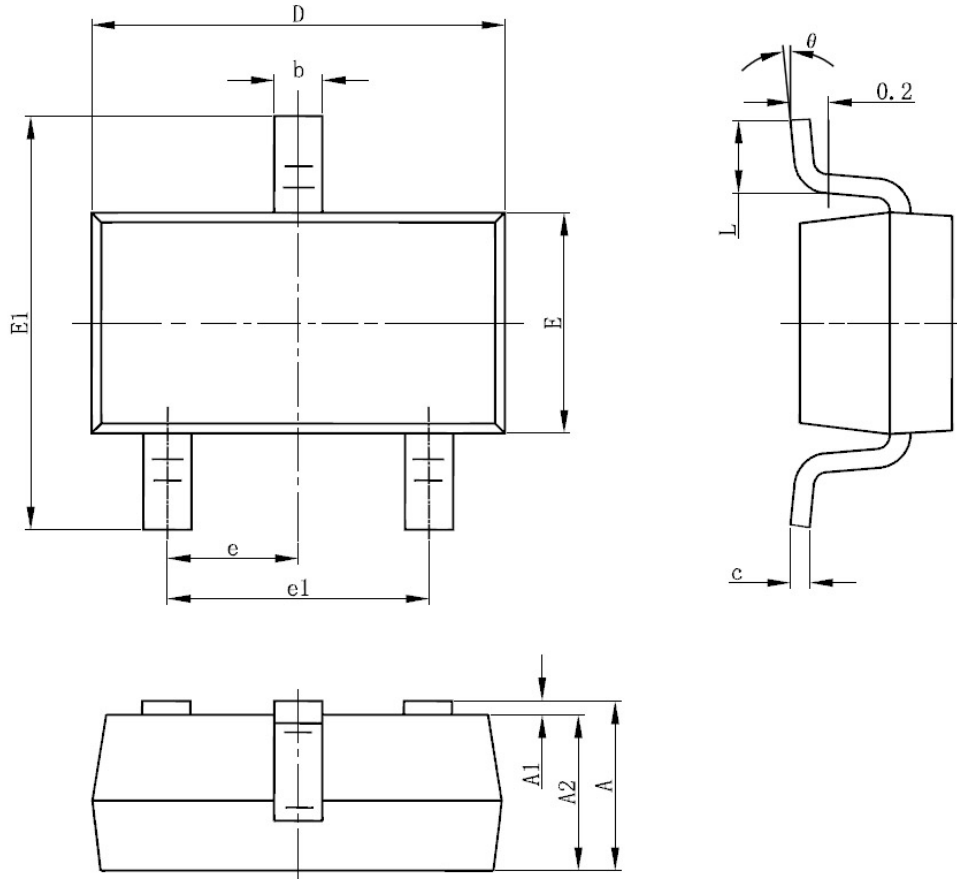


Fig.8 Gate Charge Waveform

## Package Dimension

### SOT23







### Dimensions



SYMBOL	Millimeters		Inches	
	MIN	MAX	MIN	MAX
<b>A</b>	0.900	1.200	0.035	0.043
<b>A1</b>	0.000	0.100	0.000	0.004
<b>A2</b>	0.900	1.100	0.035	0.039
<b>b</b>	0.300	0.500	0.012	0.020
<b>c</b>	0.080	0.150	0.003	0.006
<b>D</b>	2.800	3.000	0.110	0.118
<b>E</b>	1.200	1.400	0.047	0.055
<b>E1</b>	2.250	2.550	0.089	0.100
<b>e</b>	0.950 (TYP)		0.037 (TYP)	
<b>e1</b>	1.800	2.000	0.071	0.079
<b>L</b>	0.550 REF		0.022 REF	
<b>L1</b>	0.300	0.500	0.012	0.020
<b><math>\theta</math></b>	0°	8°	0°	6°

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